

MITSUBISHI HIGH SPEED CMOS M74HC03P/FP/DP

QUADRUPLE 2-INPUT POSITIVE NAND GATE WITH OPEN-DRAIN OUTPUTS

DESCRIPTION

The M74HC03 is a semiconductor integrated circuit consisting of four 2-input positive-logic NAND gates usable as negative-logic NOR gates, with open-drain outputs.

FEATURES

- Open-drain outputs
- High-speed: 10ns typ. ($C_L=15\text{pF}$, $V_{CC}=5\text{V}$)
- Low power dissipation: $5\mu\text{W}/\text{package}$, max ($V_{CC}=5\text{V}$, $T_a=25^\circ\text{C}$, quiescent state)
- High noise margin: 30% of V_{CC} , min ($V_{CC}=4.5\text{V}$, 6V)
- Capable of driving 10 74LS TTL loads
- Wide operating voltage range: $V_{CC}=2\sim 6\text{V}$
- Wide operating temperature range: $T_a=-40\sim +85^\circ\text{C}$

APPLICATION

General purpose, for use in industrial and consumer digital equipment.

FUNCTIONAL DESCRIPTION

Use of silicon gate technology allows the M74HC03 to maintain the low power dissipation and high noise margin characteristics of the standard CMOS logic 4000B series while giving high-speed performance equivalent to the 74LS03.

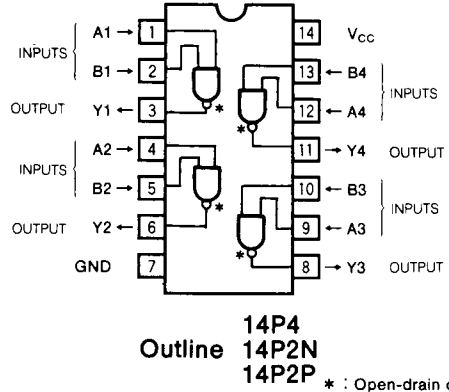
Open-drain outputs allow a versatile selection of high output impedances by connecting external load resistors. This enables "AND ties" which are not possible using normal gates. When both inputs A and B are high, the output Y will become low, and when at least one of the inputs is low, Y will become high.

Note that this IC differs from the 74LS03 and a voltage higher than V_{CC} can not be applied to the output.

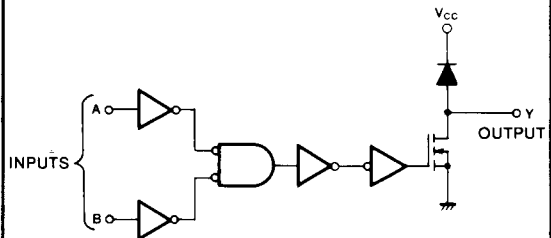
FUNCTION TABLE

Inputs		Output
A	B	Y
L	L	H
L	H	H
H	L	H
H	H	L

PIN CONFIGURATION (TOP VIEW)



LOGIC DIAGRAM (EACH GATE)



QUADRUPLE 2-INPUT POSITIVE NAND GATE WITH OPEN-DRAIN OUTPUTS

ABSOLUTE MAXIMUM RATINGS ($T_a = -40 \sim +85^\circ\text{C}$, unless otherwise noted)

Symbol	Parameter	Conditions	Ratings	Unit
V_{CC}	Supply voltage		$-0.5 \sim +7.0$	V
V_I	Input voltage		$-0.5 \sim V_{CC} + 0.5$	V
V_O	Output voltage		$-0.5 \sim V_{CC} + 0.5$	V
I_{IK}	Input protection diode current	$V_I < 0V$	-20	mA
		$V_I > V_{CC}$	20	
I_{OK}	Output parasitic diode current	$V_O < 0V$	-20	mA
		$V_O > V_{CC}$	20	
I_O	Output current per output pin		+25	mA
I_{CC}	Supply/GND current	V_{CC}, GND	± 50	mA
P_D	Power dissipation	(Note 1)	500	mW
T_{stg}	Storage temperature range		$-65 \sim +150$	$^\circ\text{C}$

Note 1 : M74HC03FP, $T_a = -40 \sim +60^\circ\text{C}$ and $T_a = 60 \sim 85^\circ\text{C}$ are derated at $-6\text{mW}/^\circ\text{C}$.
M74HC03DP, $T_a = -40 \sim +50^\circ\text{C}$ and $T_a = 50 \sim 85^\circ\text{C}$ are derated at $-5\text{mW}/^\circ\text{C}$.

RECOMMENDED OPERATING CONDITIONS ($T_a = -40 \sim +85^\circ\text{C}$)

Symbol	Parameter	Limits			Unit
		Min	Typ	Max	
V_{CC}	Supply voltage	2		6	V
V_I	Input voltage	0		V_{CC}	V
V_O	Output voltage	0		V_{CC}	V
T_{opr}	Operating temperature range	-40		+85	$^\circ\text{C}$
t_r, t_f	Input risetime, falltime	$V_{CC} = 2.0V$		1000	ns
		$V_{CC} = 4.5V$		500	
		$V_{CC} = 6.0V$		400	

ELECTRICAL CHARACTERISTICS

Symbol	Parameter	Test conditions	Limits					Unit	
			$V_{CC}(V)$	25 $^\circ\text{C}$			$-40 \sim +85^\circ\text{C}$		
				Min	Typ	Max	Min		Max
V_{IH}	High-level input voltage	$V_O = 0.1V, V_{CC} = 0.1V$ $ I_O = 20\mu A$	2.0	1.5			1.5	V	
			4.5	3.15			3.15		
			6.0	4.2			4.2		
V_{IL}	Low-level input voltage	$V_O = V_{CC} - 0.1V$ $ I_O = 20\mu A$	2.0			0.5	0.5	V	
			4.5			1.35	1.35		
			6.0			1.8	1.8		
V_{OL}	Low-level output voltage	$V_I = V_{IH}$	$I_{OL} = 20\mu A$	2.0			0.1	0.1	V
				4.5			0.1	0.1	
			$I_{OL} = 20\mu A$	6.0			0.1	0.1	
				4.5			0.26	0.33	
					6.0			0.26	
I_{IH}	High-level input current	$V_I = 6V$	6.0			0.1	1.0	μA	
I_{IL}	Low-level input current	$V_I = 0V$	6.0			-0.1	-1.0	μA	
I_O	Maximum output leakage current	$V_I = V_{IH}, V_{IL}, V_O = V_{CC}$	6.0			0.5	5.0	μA	
		$V_I = V_{IH}, V_{IL}, V_O = GND$	6.0			-0.5	-5.0		
I_{CC}	Quiescent supply current	$V_I = V_{CC}, GND, I_O = 0\mu A$	6.0			1.0	10.0	μA	

QUADRUPLE 2-INPUT POSITIVE NAND GATE WITH OPEN-DRAIN OUTPUTS

SWITCHING CHARACTERISTICS ($V_{CC} = 5V, T_a = 25^\circ C$)

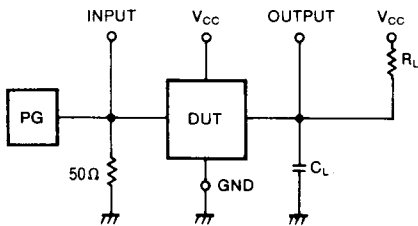
Symbol	Parameter	Test conditions	Limits			Unit
			Min	Typ	Max	
t_{THL}	High-level to low-level output transition time	$R_L = 1k\Omega$ $C_L = 15pF$ (Note 3)			10	ns
t_{PLH}	Low-level to high-level and high-level to low-level	$R_L = 1k\Omega, C_L = 5pF$ (Note 3)			20	ns
t_{PHL}	output propagation time	$R_L = 1k\Omega, C_L = 15pF$ (Note 3)			20	ns

SWITCHING CHARACTERISTICS ($V_{CC} = 2\sim 6V, T_a = -40\sim +85^\circ C$)

Symbol	Parameter	Test conditions	Limits					Unit	
			25°C			-40~+85°C			
			$V_{CC}(V)$	Min	Typ	Max	Min		Max
t_{THL}	High-level to low-level output transition time		2.0			75		95	ns
			4.5			15		19	
			6.0			13		16	
t_{PLH}	Low-level to high-level and high-level to low-level	$R_L = 1k\Omega$ $C_L = 50pF$ (Note 3)	2.0			125		158	ns
			4.5			25		32	
			6.0			21		27	
t_{PHL}	output propagation time		2.0			125		158	ns
			4.5			25		32	
			6.0			21		27	
C_i	Input capacitance					10		10	pF
C_o	Output capacitance	A or B = GND				10		10	pF
C_{PD}	Power dissipation capacitance (Note 2)				11				pF

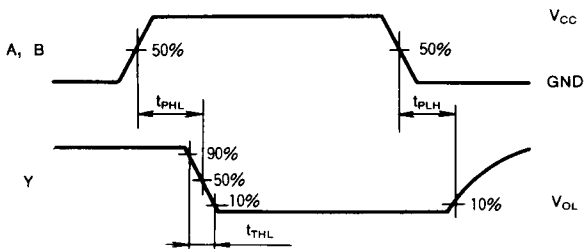
Note 2 : C_{PD} is the internal capacitance of the IC calculated from operation supply current under no-load conditions. (per gate)
The power dissipation during operation under no-load conditions is calculated using the following formula:
 $P_D = C_{PD} \cdot V_{CC}^2 \cdot f_i + I_{CC} \cdot V_{CC}$

Note 3 : Test Circuit



- (1) The pulse generator (PG) has the following characteristics (10%~90%): $t_r = 6ns, t_f = 6ns$
- (2) The capacitance C_L includes stray wiring capacitance and the probe input capacitance.

TIMING DIAGRAM



MITSUBISHI HIGH SPEED CMOS
PACKAGE OUTLINES

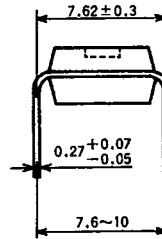
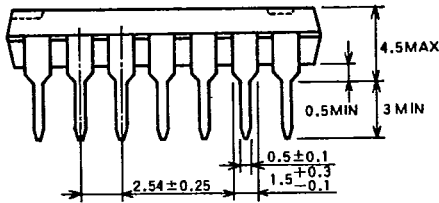
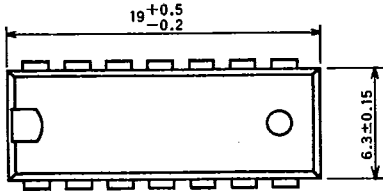
6249827 MITSUBISHI (DGTL LOGIC)

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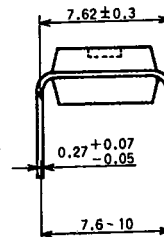
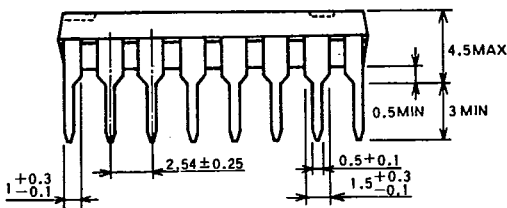
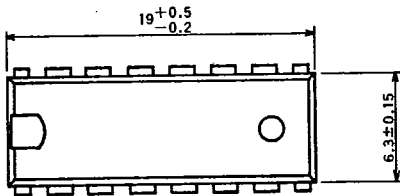
TYPE 14P4 14-PIN MOLDED PLASTIC DIP

Dimension in mm



TYPE 16P4 16-PIN MOLDED PLASTIC DIP

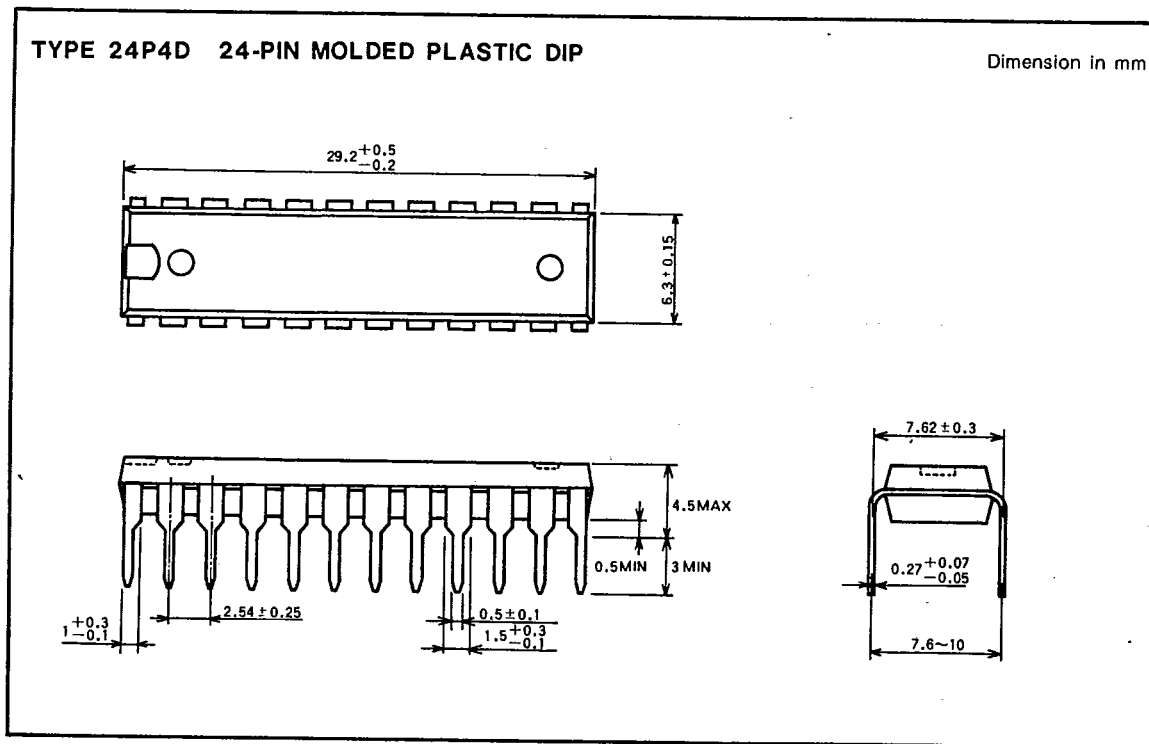
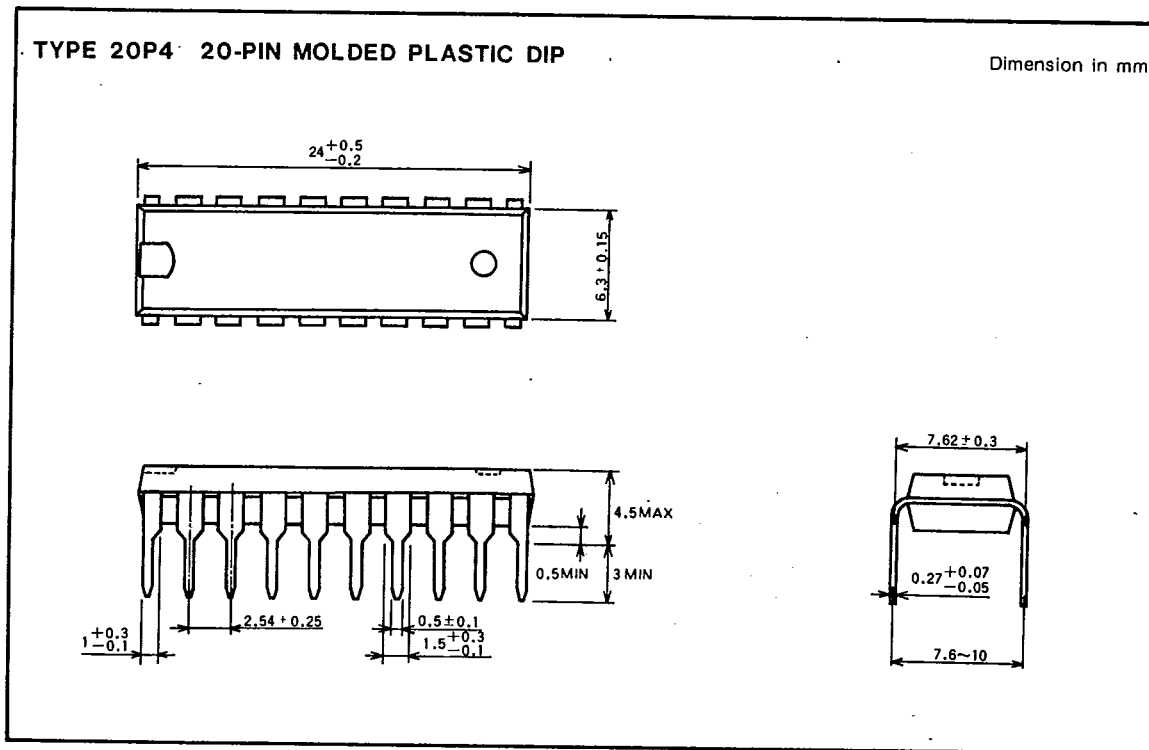
Dimension in mm



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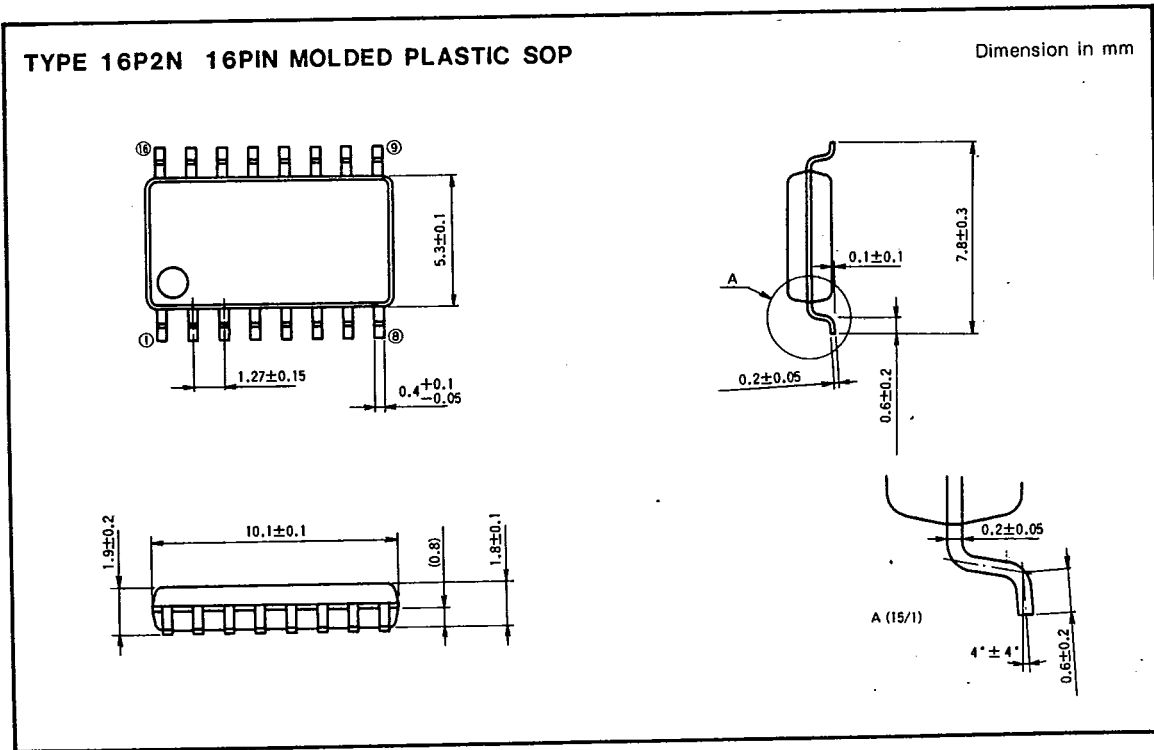
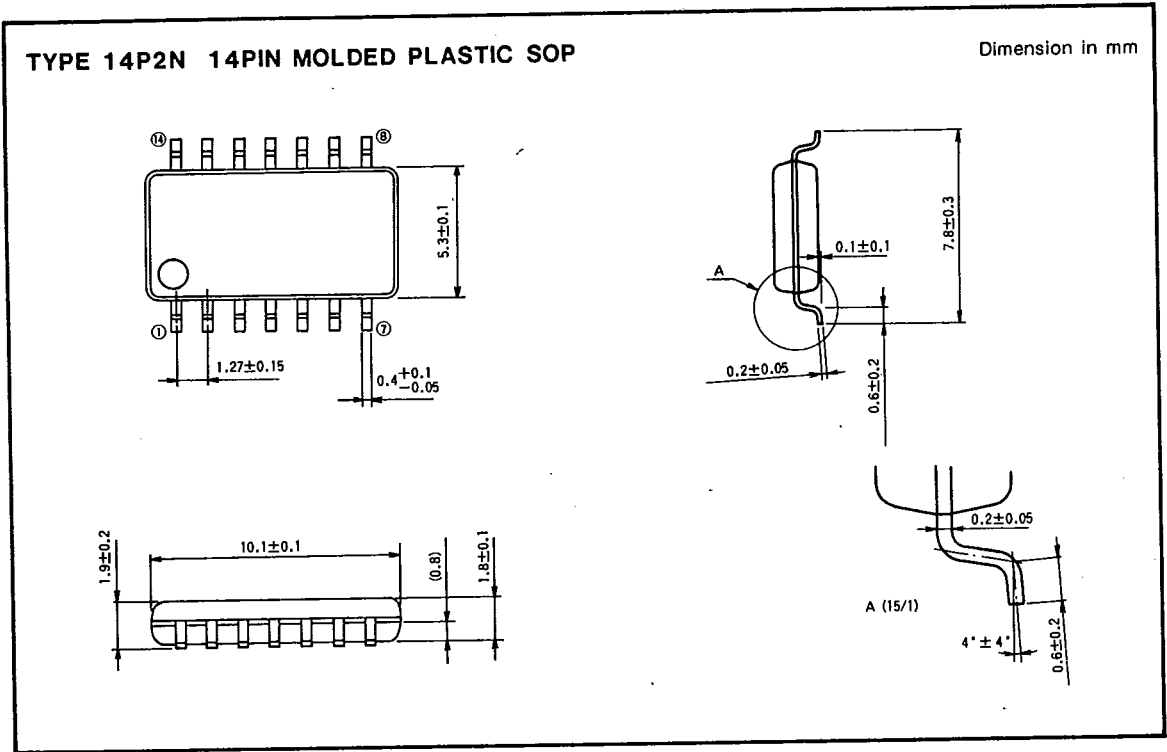


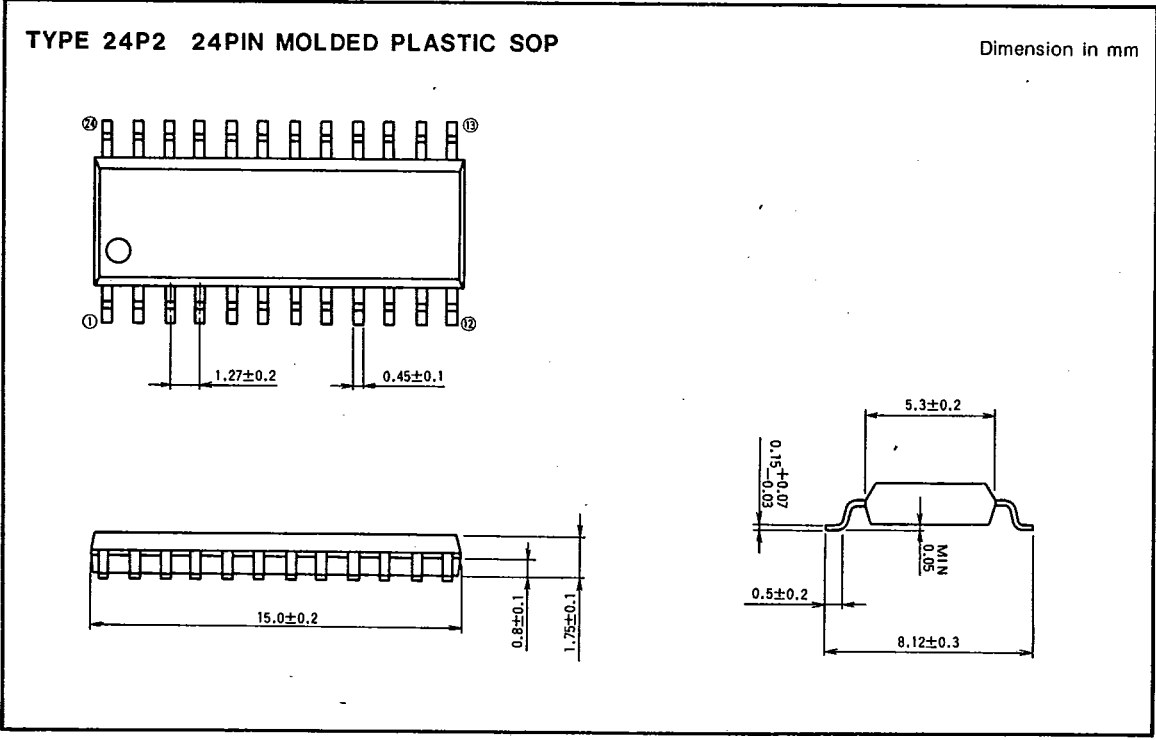
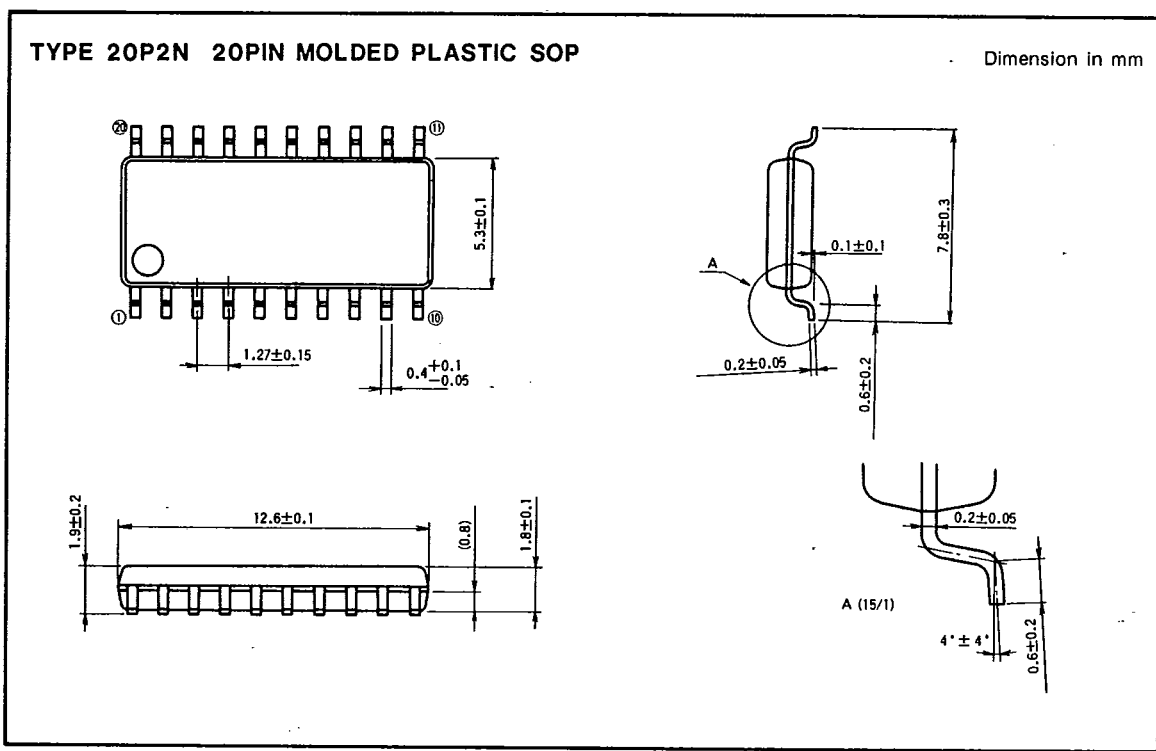
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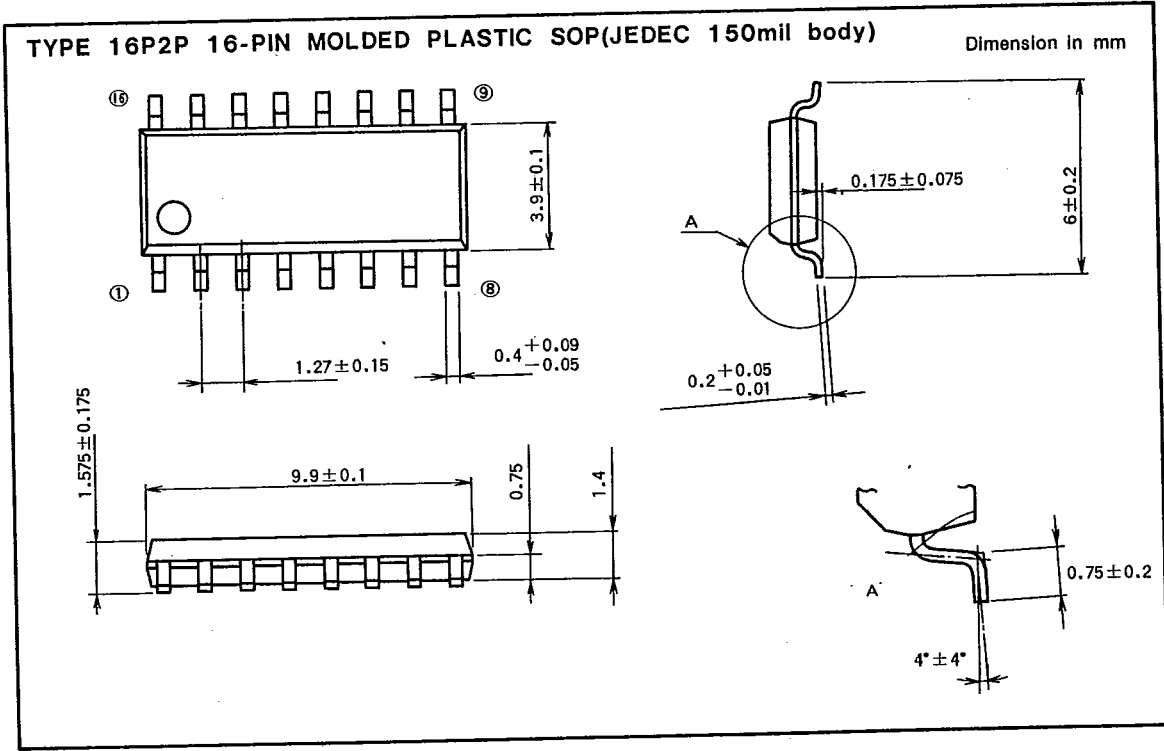
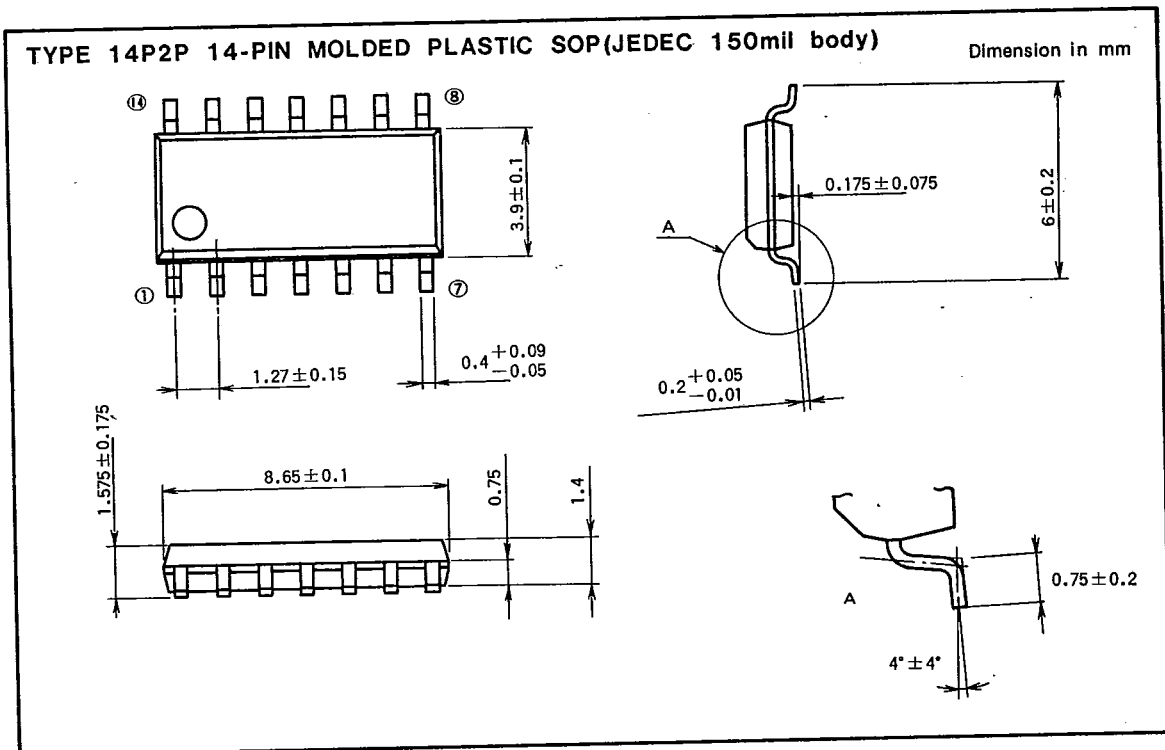
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91D 12854 D T-90-20

